



FORM PTO-1449 (Modified)		ATTY. DOCKET NO. FIS9-2003-0238US1	SERIAL NO. 10/707,842
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT		APPLICANT: Haining S. Yang, et al.	
(Use several sheets if necessary)		FILING DATE: 01/16/2004	GROUP: Unassigned

REFERENCE DESIGNATION		U.S. PATENT DOCUMENTS				
EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPRO.)
WL	6,228,694 B1	5/8/2001	Doyle et al.	T	T	
WL	6,406,973 B1	6/18/2002	Lee			
WL	6,281,532 B1	8/28/2001	Doyle et al.			
WL	5,683,934	11/4/97	Candelaria			
WL	6,368,931 B1	4/9/2002	Kuhn, et al.			
WL	5,310,446	5/10/94	Konishi et al.			
WL	4,853,076	8/1/89	Tsaur et al.			
WL	US 2002/0090791 A1	7/11/2002	Doyle et al.			
WL	US 2002/0074598 A1	6/20/2002	Doyle et al.			
WL	6,509,618 B2	01/21/2003	Jan et al.			
WL	6,476,462 B2	11/5/2002	Shimizu et al.			
WL	6,362,082 B1	3/26/2002	Doyle et al.			
WL						
WL	5,565,697	10/15/96	Asakawa et al.			
WL	US 2003/0040158 A1	2/27/2003	Saitoh			
WL	US 2002/0086472 A1	7/4/2002	Roberds et al.			
WL	6,521,964 B1	2/18/2003	Jan et al.			
WL	6,506,652	01/14/03	Jan, et al.			

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
							YES
							NO

## OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER		DATE CONSIDERED
		4/14/2005

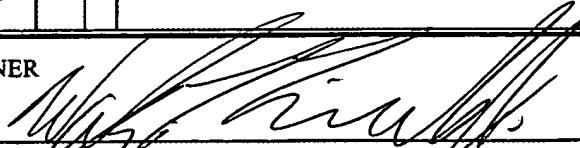
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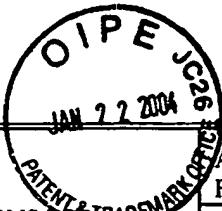
REFERENCE DESIGNATION		U.S. PATENT DOCUMENTS					
EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPRO.)	
WL	5,081,513	1/14/1992	Jackson, et al.	7			
WL	3,602,841	8/31/1971	McGroddy	7			
WL	6,531,740	3/11/2003	Bosco, et al.				
WL	6,531,369	3/11/2003	Ozkan, et al.				
WL	6,501,121	12/31/2002	Yu, et al.				
WL	6,498,358	12/24/2002	Lach, et al.				
WL	6,493,497	12/10/2002	Ramdani, et al.				
WL	6,403,975	6/11/2002	Brunner, et al.				
WL	6,361,885	3/26/2002	Chou				
WL	6,255,169	7/3/2001	Li, et al.				
WL	6,246,095	6/12/2001	Brady, et al.				
WL	6,165,383	12/26/2000	Chou				
WL	6,133,071	10/17/2000	Nagai				
WL	6,046,464	4/4/2000	Schetzina				
WL	6,025,280	2/15/2000	Brady, et al.				

FOREIGN PATENT DOCUMENTS						
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(Use several sheets if necessary)	APPLICANT: Haining S. Yang, et al.	
	FILING DATE: 01/16/2004	GROUP: Unassigned

REFERENCE DESIGNATION		U.S. PATENT DOCUMENTS				
EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPRO.)
WL	5,940,736	8/17/1999	Brady, et al.	1	1	
WL	5,880,040	3/9/1999	Sun, et al.			
WL	5,861,651	1/19/1999	Brasen, et al.			
WL	5,679,965	10/21/1997	Schetzina			
WL	5,670,798	9/23/1997	Schetzina			
WL	5,561,302	10/1/1996	Candelaria			
WL	5,471,948	12/5/1995	Burroughes, et al.			
WL	5,459,346	10/17/1995	Asakawa, et al.			
WL	5,391,510	2/21/1995	Hsu, et al.			
WL	5,371,399	12/6/1994	Burroughes, et al.			
WL	5,108,843	4/28/1992	Ohtaka, et al.			
WL	5,060,030	10/22/1991	Hoke			
WL	4,958,213	9/18/1990	Eklund, et al.			
WL	4,665,415	5/12/1987	Esaki, et al.			

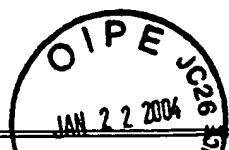
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REFERENCE DESIGNATION		U.S. PATENT DOCUMENTS				
EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPRO.)
WL	5,989,978	11/23/1999	Peidous			
WL	6,284,626	9/4/2001	Kim			
WL	6,274,444	8/14/2001	Wang			
WL	6,261,964	7/17/2001	Wu, et al.			
WL	6,221,735	4/24/2001	Manley, et al.			
WL	6,117,722	9/12/2000	Wuu, et al.			
WL	6,107,143	8/22/2000	Park, et al.			
WL	6,090,684	7/18/2000	Ishitsuka, et al.			
WL	6,066,545	5/23/2000	Doshi, et al.			
WL	6,008,126	12/28/1999	Leedy			
WL	5,946,559	8/31/1999	Leedy			
WL	5,840,593	11/24/1998	Leedy			
WL	5,592,018	1/7/1997	Leedy			
WL	5,592,007	1/7/1997	Leedy			
WL	5,571,741	11/5/1996	Leedy			

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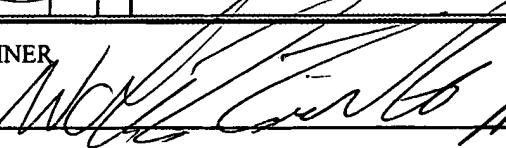
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WL	5,557,122	9/17/1996	Shrivastava, et al.			
WL	5,354,695	10/11/1994	Leedy			
WL	5,134,085	7/28/1992	Gilgen, et al.			
WL	5,006,913	4/9/1991	Sugahara, et al.			
WL	4,952,524	8/28/1990	Lee, et al.			
WL	4,855,245	8/8/1989	Neppl, et al.			
WL	2002/0086497	07-04-2002	Kwok			
WL	5,960,297	09-28-1999	Saki			
WL	6,403,486	06-11-2002	Lou			
WL	6,284,623	09-04-2001	Zhang et al.			
WL	2003/0032261	02-13-2003	Yeh et al.			
WL	2003/0057184	03-27-2003	Yu et al.			
WL	6,265,317	07-24-2001	Chiu et al.			
WL	2003/0067035	04-10-2003	Tews et al.			
WL	6,461,936	10-08-2002	von Ehrenwall			
WL	6,319,794	11-20-2001	Akatsu et al.			
WL	2001/0009784	07-26-2001	Ma et al.			

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**OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)**

WL		Kern Rim, et al., "Transconductance Enhancement in Deep Submicron Strained-Si <i>n</i> -MOSFETs", International Electron Devices Meeting, 26, 8, 1, IEEE, September 1998.
WL		Kern Rim, et al., "Characteristics and Device Design of Sub-100 nm Strained Si N- and PMOSFETs", 2002 Symposium On VLSI Technology Digest of Technical Papers, IEEE, pp 98-99.
WL		Gregory Scott, et al., "NMOS Drive Current Reduction Caused by Transistor Layout and Trench Isolation Induced Stress", International Electron Devices Meeting, 34.4.1, IEEE, September 1999.
WL		F. Ootsuka, et al., "A Highly Dense, High-Performance 130nm node CMOS Technology for Large Scale System-on-a-Chip Application", International Electron Devices Meeting, 23.5.1, IEEE, April 2000.
WL		Shinya Ito, et al., "Mechanical Stress Effect of Etch-Stop Nitride and its Impact on Deep Submicron Transistor Design", International Electron Devices Meeting, 10.7.1, IEEE, April 2000.
WL		A. Shimizu, et al., "Local Mechanical-Stress Control (LMC): A New Technique for CMOS-Performance Enhancement", International Electron Devices Meeting, IEEE, March 2001.
WL		K. Ota, et al., "Novel Locally Strained Channel Technique for high Performance 55nm CMOS", International Electron Devices Meeting, 22.2.1, IEEE, February 2002.

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